

MCM68766

8192 × 8-BIT UV ERASABLE PROM

The MCM68766 is a 65,536-bit Erasable and Electrically Reprogrammable PROM designed for system debug usage and similar applications requiring nonvolatile memory that could be reprogrammed periodically, or for replacing 64K ROMs for fast turnaround time. The transparent window on the package allows the memory content to be erased with ultraviolet light.

For ease of use, the device operates from a single power supply that has an output enable control and is pin-for-pin compatible with the MCM68366 mask programmable ROMs, which are available for large volume production runs of systems initially using the MCM68766.

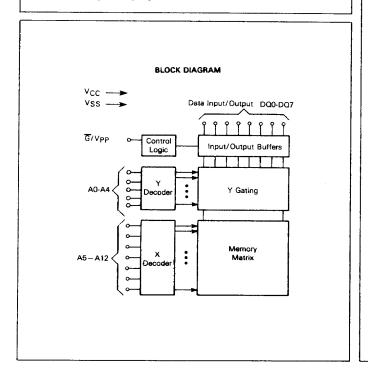
- Single +5 V Power Supply
- Organized as 8192 Bytes of 8 Bits
- Fully TTL Compatible
- Maximum Access Time = 450 ns MCM68766

400 ns MCM68766-40

350 ns MCM68766-35

300 ns MCM68766-30

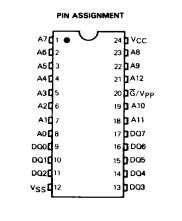
- Standard 24-Pin DIP for EPROM Upgradability
- Pin Compatible to MCM68366 Mask Programmable ROM
- Low Power Dissipation 85 mA Active Maximum
- Fast Programming Algorithm Possible



MOS

(N-CHANNEL, SILICON-GATE)
8192 × 8-BIT
UV ERASABLE
PROGRAMMABLE READ
ONLY MEMORY





Pin Names
A Address DQ Data Input/Output G/Vpp Output Enable/Program VCC +5 V Power Supply VSS Ground

MCM68766

ABSOLUTE MAXIMUM RATINGS

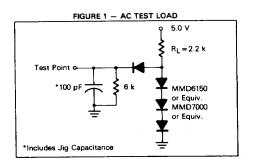
Rating	Value	Unit
Temperature Under Bias	- 10 to +80	°C
Operating Temperature Range	0 to +70	°C
Storage Temperature	- 65 to + 125	°C
All Input or Output Voltages with Respect to VSS	+6 to -0.3	Vdc
Vpp Supply Voltage with Respect to VSS	+ 28 to - 0.3	Vdc

This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields; however, it is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltages to this high-impedance circuit.

NOTE: Permanent device damage may occur if ABSOLUTE MAXIMUM RATINGS are exceeded. Functional operation should be restricted to RECOMMENDED OPERATING CONDITIONS. Exposure to higher than recommended voltages for extended periods of time could affect device reliability.

MODE SELECTION

		Pin Number						
Mode	9-11, 13-17, DQ	12 VSS	20 G/V _{PP}	24 VCC				
Read	Data Out	Vss	VIL	Vcc				
Output Disable	High-Z	Vss	VIH	Vcc				
Program	Data in	٧ss	Pulsed V _{ILP} to VIHP	VCC				



DC OPERATING CONDITIONS AND CHARACTERISTICS

(Full operating voltage and temperature range unless otherwise noted)

CAPACITANCE If = 1.0 MHz, $T_A = 25$ °C, $V_{CC} = 5$ V periodically sampled rather than 100% tested

Characteristic	Symbol	Тур	Max	Unit
input Capacitance (V _{in} = 0 V) Except G/Vpp Input Capacitance (G/Vpp)	Cin	4.0	6.0	рF
Output Capacitance (Vout = 0 V)	Cin	60	100	рF
agricus apparentation (AOMI = 0.4)	Cout	8.0	12	DF

Capacitance measured with a Boonton Meter or effective capacitance calculated from the equation: $C = I\Delta_t/\Delta V$.

RECOMMENDED DC OPERATING CONDITIONS

	Parameter	Symbol	Min	Nom	Max	Unit
Supply Voltage	MCM68766C, C35, C4		4.75	5.0	5.25	V
	MCM68766C30-10, C35-1	0	4.50	5.0	5.50	
Input High Voltage		VIH	2.0	-	V _{CC} + 1.0	V
Input Low Voltage		VIL	-0.1		0.8	V

DC OPERATING CHARACTERISTICS

Characteristic	Condition	Symbol	Min	Тур	Max	Units
Address Input Sink Current	$V_{in} = 5.25 \text{ V}$	lin			10	uA
Output Leakage Current	V _{out} = 5.25 V	ILO		<u> </u>	10	μA
G/Vpp Input Sink Current	G/VPP=0.4 V		_	_	100	μA
	$\overline{G}/V_{PP} = 2.4 \text{ V}$		_	_	100	μA
VCC Supply Current (Outputs Open)	$\overline{G}/V_{PP} = V_{IL}$	¹cc			85	mA
Output Low Voltage	I _{OL} = 2.1 mA	VOL	_	_	0.45	V
Output High Voltage	I _{OH} = -400 μA	Voн	2.4	_	-	V

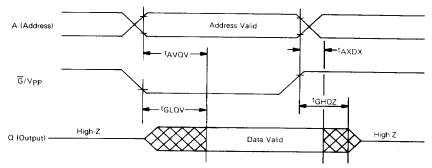
AC OPERATING CONDITIONS AND CHARACTERISTICS

(Full operating voltage and temperature range unless otherwise noted)

Input Pulse Levels	Output Timing Levels. 0.8 Volt and 2.0 Volts Output Load. See Figure 1
Thrilling Levels	

	Syr	nbol	MCMi	68766C 10		68766C 15		8766C 0	мсм	8766C	
Characteristic	Standard	Alternate	Min	Max	Min	Max	Min	Max	Min	Max	Units
Address Valid to Output Valid $(\overline{G} = V_{ L})$	tAVQV	†ACC	-	300		350	<u> </u>	400	-	450	ns
Output Enable to Output Valid	t _{GLQV}	1OE		120	-	150	_	150		150	ns
Output Disable to Output High Z	tGHQZ	1DF	0	100	0	100	0	100	0	100	ns
Data Hold from Address (G = V _{IL})	tAXDX	tон	0		0	_	0		0	_	ns

READ MODE TIMING DIAGRAM



DC PROGRAMMING CONDITIONS AND CHARACTERISTICS $^{\{T}{A}=25\pm~5\,^{\circ}\text{C})$

RECOMMENDED PROGRAMMING OPERATING CONDITIONS

Parameter	Symbol	Min	Nom	Max	Unit
Supply Voltage	Vcc	4.75	5.0	5.25	V
Input High Voltage for All Addresses and Data	ViH	2.2		VCC + 1	V
Input Low Voltage for All Addresses and Data	VIL	0.1		0.8	V
Program Pulse Input High Voltage	VIHP	24	25	26	٧
Program Pulse Input Low Voltage	VILP	2.0	Vcc	6.0	V

PROGRAMMING OPERATION DC CHARACTERISTICS

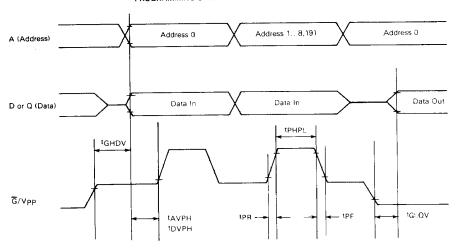
Characteristic	Condition	Symbol	Min	Тур	Max	Unit
Address Input Sink Current	V _{in} = 5.25 V	ILI	-	-	16	μΑ
Vpp Program Pulse Supply Current (Vpp = 25 V ± 1 V)	-	¹ PH			30	mΑ
Vpp Supply Current (Vpp = 2.4 V)		IPL = IGH	-		100	μΑ
VCC Supply Current (Vpp=5 V)		Icc	_	-	85	mA

AC PROGRAMMING CONDITIONS AND CHARACTERISTICS

	Syn	Symbol			
Characteristic	Standard	Alternate	Min	Max	Unit
Address Setup Time	^t AVPH	†AS	2.0	-	μs
Data Setup Time	tDVPH	tDS	2.0	-	μS
Output Enable to Valid Data	†GLQV	†OE	150		ns
Output Disable to Data In	†GHDV	todd	2.0		μS
Program Pulse Width	1PHPL	t _{PW}	1.9	2.1	ms
Program Pulse Rise Time	t _{PR}	tpR	0.5	2.0	μS
Program Pulse Fall Time	tpF	tpF	0.5	2.0	μS
Cumulative Programming Time Per Word*	tcp	tCP	12	50	ms

^{*}If less than 25, two-millisecond pulses are required to verify programming then 5 additional two-millisecond pulses are required to ensure proper operating margins (i.e., 2 ms+5×2 ms=12 ms minimum t_{CP}).

PROGRAMMING OPERATION TIMING DIAGRAM



MCM68766

PROGRAMMING INSTRUCTIONS

Before programming, the memory should be submitted to a full erase operation to ensure that every bit is in the "1" state (represented by Output High). Data is entered by programming zeros (Output Low) into the required bits. The words are addressed the same way as in the READ operation. A programmed "0" can only be changed to a "1" by ultraviolet light erasure.

To set the memory up for Program Mode, the \overline{G}/Vpp input (Pin 20) should be between +2.0 and +6.0 V, which will three-state the outputs and allow data to be set up on the DQ terminals. The V_{CC} voltage is the same as for the Read operation. Only "0's" will be programmed when "0's" and "1's" are entered in the 8-bit data word.

After address and data setup, 25-volt programming pulse (V)_H to V|_HP) is applied to the \overline{G} /VPP input. The program pulse width is 2 ms and the maximum program pulse amplitude is 26 V.

Multiple MCM68766s may be programmed in parallel by connecting like inputs and applying the program pulse to the \overline{G}/Vpp inputs. Different data may be programmed into multiple MCM68766s connected in parallel by selectively applying the programming pulse only to the MCM68766s to be programmed.

READ OPERATION

After access time, data is valid at the outputs in the Read mode. With $\overline{G}/Vpp="0"$ the outputs are enabled; with $\overline{G}/Vpp="1"$ the outputs are three-stated.

Multiple MCM68766s may share a common data bus with like outputs OR-tied together. In this configuration only one \bar{G}/Vpp input should be low and no other device outputs should be active on the same bus. This will prevent data contention on the bus.

ERASING INSPUCTIONS

The MCM68766 can be erased by exposure to high intensity shortwave ultraviolet light, with a wavelength of 2537 angstroms. The recommended integrated dose (i.e., UV-intensity X exposure time) is 15 Ws/cm². As an example, using the "Model 30-000" UV Eraser (Turner Designs, Mountain View, CA 94043) the ERASE-time is 36 minutes. The lamps should be used without shortwave filters and the MCM68766 should be positioned about one inch away from the UV-tubes

RECOMMENDED OPERATING PROCEDURES

After erasure and reprogramming of the EPROM, it is recommended that the quartz window be covered with an opaque self-adhesive cover. It is important that the self-adhesive cover not leave any residue on the quartz if it is removed to allow another erasure.

FAST PROGRAMMING ALGORITHM

This device is capable of the fast programming algorithm as shown by the following flow chart. This algorithm allows for faster programming time with increased operating margins and improved reliability of data storage.

FAST PROGRAMMING ALGORITHM FLOW CHART

